

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT  
(IECEE) CB SCHEME

CB TEST CERTIFICATE

Product	Touch key device
Name and address of the applicant	Silicon Labs 400 West Cesar Chavez, TX 78701, Austin United States of America
Name and address of the manufacturer	Silicon Labs 400 West Cesar Chavez, TX 78701, Austin United States of America
Name and address of the factory	<input type="checkbox"/> Additional information on page 2
Note: When more than one factory, please report on page 2	Silicon Labs 400 West Cesar Chavez, TX 78701, Austin United States of America
Ratings and principal characteristics	1.8-3.6 VDC, max 4.5 mA, Software Class B
Trademark (if any)	Silicon labs
Customer's Testing Facility (CTF) Stage used	
Model / Type Ref.	CPT213B
Additional information (if necessary may also be reported on page 2)	<input type="checkbox"/> Additional information on page 2 The product fulfils the requirements of IEC 60335-1:2010+A1:2013+A2:2016, clauses 19.11-19.11.3 and Annex R (Table R.1)
A sample of the product was tested and found to be in conformity with	IEC 60730-1:2013 National differences: EU Group Differences
As shown in the Test Report Ref. No. which forms part of this Certificate	2213912.50 (consisting of sub reports with suffixes A, B and C)

This CB Test Certificate is issued by the National Certification Body

Meander 1051, NL-6825 MJ Arnhem, Netherlands  
DEKRA Certification B.V.

